SLRS007B - NOVEMBER 1986 - REVISED NOVEMBER 1995

• 1-A Output-Current Capability Per Driver

• Applications Include Half-H and Full-H Solenoid Drivers and Motor Drivers

- **Designed for Positive-Supply Applications**
- Wide Supply-Voltage Range of 4.5 V to 36 V
- **TTL- and CMOS-Compatible High-Impedance Diode-Clamped Inputs**
- Separate Input-Logic Supply
- **Thermal Shutdown**
- Internal ESD Protection
- Input Hysteresis Improves Noise Immunity
- **3-State Outputs**
- **Minimized Power Dissipation**
- Sink/Source Interlock Circuitry Prevents **Simultaneous Conduction**
- No Output Glitch During Power Up or **Power Down**
- Improved Functional Replacement for the **SGS L293**

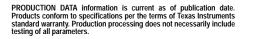
description

The SN754410 is a quadruple high-current half-H driver designed to provide bidirectional drive currents up to 1 A at voltages from 4.5 V to 36 V. The device is designed to drive inductive loads such as relays, solenoids, dc and bipolar stepping motors, as well as other high-current/high-voltage loads in positive-supply applications.

All inputs are compatible with TTL-and low-level CMOS logic. Each output (Y) is a complete totem-pole driver with a Darlington transistor sink and a pseudo-Darlington source. Drivers are enabled in pairs with drivers 1 and 2 enabled by 1,2EN and drivers 3 and 4 enabled by 3,4EN. When an enable input is high, the associated drivers are enabled and their outputs become active and in phase with their inputs. When the enable input is low, those drivers are disabled and their outputs are off and in a high-impedance state. With the proper data inputs, each pair of drivers form a full-H (or bridge) reversible drive suitable for solenoid or motor applications.

A separate supply voltage (V_{CC1}) is provided for the logic input circuits to minimize device power dissipation. Supply voltage V_{CC2} is used for the output circuits.

The SN754410 is designed for operation from -40° C to 85° C.







NE PACKAGE (TOP VIEW) 16 🛛 V_{CC1} 1,2EN 15 4A 1A [2 1Y 🛛 3 14 4Y ſ HEAT SINK AND Г 4 13 【 L HEAT SINK AND GROUND] 12 J GROUND Γ 5 6 11 3Y 2Y [10 3A 2A | 7 9**]** 3,4EN 8 V_{CC2}

FUNCTION TABLE (each driver)

INP	uts†	OUTPUT
Α	EN	Y
н	Н	Н
L	н	L
Х	L	Z

H = high-level, L = low-level

X = irrelevant

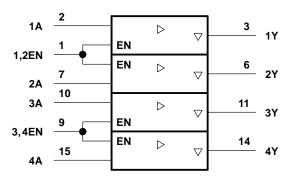
Z = high-impedance (off)

†In the thermal shutdown mode, the output is in a highimpedance state regardless of the input levels.

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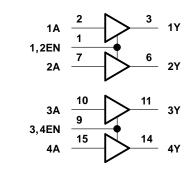
logic symbol[†]

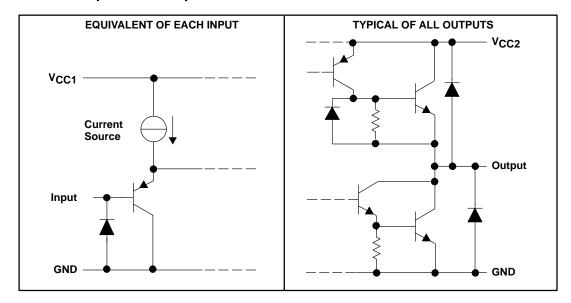


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

schematics of inputs and outputs

logic diagram







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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

$\begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{array}{cccc} & -0.5 \ V \ to \ 36 \ V \\ -3 \ V \ to \ V_{CC2} + 3 \ V \\ & \pm 2 \ A \\ & \pm 2 \ A \\ & \pm 1.1 \ A \\ & 2075 \ mW \\ & -40^\circ C \ to \ 85^\circ C \\ & -40^\circ C \ to \ 150^\circ C \end{array}$

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to network GND.

2. For operation above 25°C free-air temperature, derate linearly at the rate of 16.6 mW/°C. To avoid exceeding the design maximum virtual junction temperature, these ratings should not be exceeded. Due to variations in individual device electrical characteristics and thermal resistance, the built-in thermal overload protection can be activated at power levels slightly above or below the rated dissipation.

recommended operating conditions

	MIN	MAX	UNIT
Output supply voltage, V _{CC1}	4.5	5.5	V
Output supply voltage, V _{CC2}	4.5	36	V
High-level input voltage, VIH	2	5.5	V
Low-level input voltage, VIL	-0.3‡	0.8	V
Operating virtual junction temperature, TJ	-40	125	°C
Operating free-air temperature, T _A	-40	85	°C

[‡] The algebraic convention, in which the least positive (most negative) limit is designated as minimum, is used in this data sheet for logic voltage levels.



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electrical characteristics over recommended ranges of supply voltage and free-air temperature (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP [†]	MAX	UNIT	
VIK	Input clamp voltage	l _l = −12 r	mA		-0.9	-1.5	V	
VOH	High-level output voltage	I _{OH} = -0.5 A		V _{CC2} -1.5	V _{CC2} -1.1			
		I _{OH} = -1 A		V _{CC2} -2			V	
		$I_{OH} = -1$	A, $T_J = 25^{\circ}C$	V _{CC2} -1.8	V _{CC2} -1.4			
	Low-level output voltage	I _{OL} = 0.5 A			1	1.4		
VOL		I _{OL} = 1 A				2	V	
		$I_{OL} = 1 A$	$T_J = 25^{\circ}C$		1.2	1.8		
Varia	High-level output clamp voltage	$\frac{I_{OK} = -0.5 \text{ A}}{I_{OK} = 1 \text{ A}}$			V _{CC2} +1.4	V _{CC2} +2	V	
VOKH					V _{CC2} +1.9	V _{CC2} +2.5		
Varia	Low-level output clamp voltage		I _{OK} = 0.5 A		-1.1	-2	V	
VOKL	Low-level output clamp voltage	$I_{OK} = -1$	OK = -1 A		-1.3	-2.5	v	
	Off-state high-impedance-state	$V_{O} = V_{CC2}$ $V_{O} = 0$				500		
IOZ(off)	output current					-500	μA	
Ιн	High-level input current	V ₁ = 5.5 V				10	μΑ	
۱ _{IL}	Low-level input current	V ₁ = 0				-10	μΑ	
ICC1	Output supply current	I ^O = 0	All outputs at high level			38	mA	
			All outputs at low level			70		
			All outputs at high impedance			25		
I _{CC2}	Output supply current		All outputs at high level			33	:0 mA	
		IO = 0	All outputs at low level			20		
			All outputs at high impedance			5		

[†] All typical values are at V_{CC1} = 5 V, V_{CC2} = 24 V, T_A = 25°C.

switching characteristics, V_{CC1} = 5 V, V_{CC2} = 24 V, C_L = 30 pF, T_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN TYP MAX	UNIT
^t d1	Delay time, high-to-low-level output from A input		400	ns
t _{d2}	Delay time, low-to-high-level output from A input		800	ns
^t TLH	Transition time, low-to-high-level output		300	ns
^t THL	Transition time, high-to-low-level output	See Figure 1	300	ns
t _r	Rise time, pulse input			
t _f	Fall time, pulse input			
tw	Pulse duration			
ten1	Enable time to the high level		700	ns
t _{en2}	Enable time to the low level		400	ns
^t dis1	Disable time from the high level	See Figure 2	900	ns
t _{dis2}	Disable time from the low level		600	ns

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tf tr Input 5 V 24 V 3 V Pulse V_{CC2} 90% VCC1 90% Generator Input 1.5 V 1.5 V Α (see Note A) 10% 10% Circuit 0 V Under Output tw Test - ^td2 td1 90% VOH 3 V ΕN C_L = 30 pF 90% (see Note B) Output GND 10% 10% - Vol Ī **TEST CIRCUIT** 🖌 🕨 🕇 tthl – ttlh **VOLTAGE WAVEFORMS**

PARAMETER MEASUREMENT INFORMATION

Figure 1. Test Circuit and Switching Times From Data Inputs

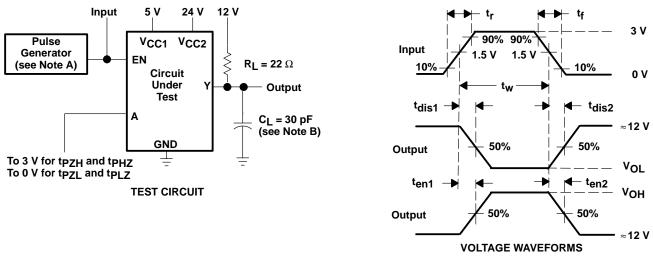


Figure 2. Test Circuit and Switching Times From Enable Inputs

NOTES: A. The pulse generator has the following characteristics: $t_f \le 10$ ns, $t_f \le 10$ ns, $t_W = 10 \mu$ s, PRR = 5 kHz, $Z_O = 50 \Omega$. B. C₁ includes probe and jig capacitance.



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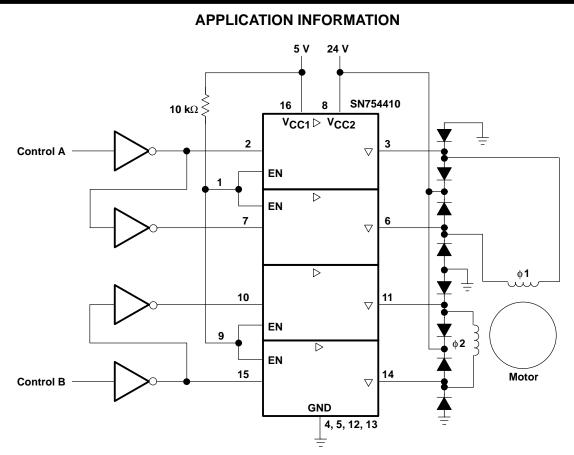


Figure 3. Two-Phase Motor Driver



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